

**Notice of References Cited**

Application/Control No.

09/961,344

Applicant(s)/Patent Under

Reexamination

LETE, GHISLAIN

Examiner

Brian Roberts

Art Unit

2662

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,571,284	05-2003	Suonvieri, Jukka	709/221
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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	S					
	T					

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<b>Notice of References Cited</b>	Application/Control No. 09/961,344	Applicant(s)/Patent Under Reexamination LETE, GHISLAIN	
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